AMENDMENTS TO THE CLAIMS

Claims 1-19. Canceled

20. (New) A scanning transmission electron microscope, comprising:

an electron beam source;

an electron beam scanning coil for scanning an electron beam emitted from said electron beam source;

an upper objective lens for irradiating the emitted electron beam passed through said coil on a sample;

a scattered electron detector for detecting a scattered electron beam among electron beams transmitted through the sample;

an electron spectrometer for dispersing said electron beams transmitted through the sample; and

an electron beam detector for detecting the electron beam coming out from said electron spectrometer, which further comprises an ultimate analyzer for analyzing elements of said sample.

21. (New) A scanning transmission electron microscope, comprising:

an electron beam source;

an electron beam scanning coil for scanning an electron beam emitted from said electron beam source;

an upper objective lens for irradiating the emitted electron beam passed through said coil on a sample;

a scattered electron detector for detecting a scattered electron beam among electron beams transmitted through the sample;

an electron spectrometer for dispersing said electron beams transmitted through the sample; and

an electron beam detector for detecting the electron beam coming out from said electron spectrometer, which further comprises an ultimate analyzer for analyzing elements of said sample,

wherein said ultimate analyzer is a computing unit either for adding or subtracting operation between the intensity of said dispersed electron beam, or a calculation result obtained based on said intensity, and the intensity of said scattered electron beam or for dividing operation to said intensity of said dispersed electron beam, or said calculation result, using the square root of said intensity of scattered electron beam as the divisor.